

Notice of References Cited

Application/Control No.

10/671,948

Applicant(s)/Patent Under
Reexamination
HASEGAWA ET AL.

Examiner

Sin J. Lee

Art Unit

1752

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	N	2002-156760	05-2002	Japan	Nio et al.	N/A
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NON-PATENT DOCUMENTS

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	U	JPO English abstract for JP 2002-156760 (Nio et al).
	V	Chemical Abstract 1991:61346 (for Jung et al, Journal of the American Chemical Society, 1991, 113(1), pg.224-32).
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.